

AWR AND PARTNERS MICROAPPS SCHEDULE

Date and Time:	Title and Company:
Tuesday, May 25 09:30	Multi-chip Module Design Challenges Josh Moore, Dustin Hoekstra AWR Corp.
Tuesday, May 25 10:10	Nonlinear Co-simulation with Real-time Channel Measurements for PCB Signal Integrity Mike Heimlich, Khaled Nikro, Harry Momjian Macquarie University; AWR Corp.; Anritsu Corp.
Tuesday, May 25 10:30	Causality Considerations for Multi-Gigabit StatEye Analysis Michael Heimlich, Scott Wedge, Ted Mido AWR Corp.; Synopsys, Inc.
Tuesday, May 25 13:10	System-Level Component Models for RF EDA Jiang Liu, Lawrence Dunleavy Modelithics, Inc.
Tuesday, May 25 13:30	Multi-Rate Harmonic Balance for Non-Linear Simulation Josh Moore AWR Corp.
Tuesday, May 25 14:10	PA Design Inclusive of Load-Pull Analysis Josh Moore, Dustin Hoekstra AWR Corp.
Tuesday, May 25 14:30	Online Design Environment Provides Interactive Datasheets for Small Signal RF Transistors – Allows Users to Generate Custom Datasheets for a Variety of Operating Conditions Sherry Hess, Uwe Knorr, Ronald Thissen AWR Corp.; Transim Technology Corp; NXP Semiconductors
Tuesday, May 25 14:50	Using AWR's iFilter™ Wizard to Efficiently Synthesize Lumped & Distributed Filters Mark Saffian AWR Corp.
Tuesday, May 25 16:30	Single Chip LNA Using High Q Inductors on a Silicon-on-Sapphire Process Duncan Widman, Yash Moghe AWR Corp.; Sapphicon Semiconductor
Wednesday, May 26 11:30	A New Approach for Nonlinear Behavioral Modeling Darren McCarthy, Johannes Benedikt Tektronix Inc.; Mesuro Limited
Wednesday, May 26 12:30	A Methodical Approach to Analyzing and Understanding the Performance of a LTE System Joel Kirshman AWR Corp.
Wednesday, May 26 14:50	The Use of Computer Clusters and Spectral and Domain Decomposition in 3D FEM Analysis John DeFord, John Dunn AWR Corp.
Thursday, May 27 09:30	Test & Measurement Migration to Integrated Simulation, Test & Measurement for M&RF Design John Leitner Rohde & Schwarz